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Understanding Embedded - FPGAs (Field Programmable Gate Array)

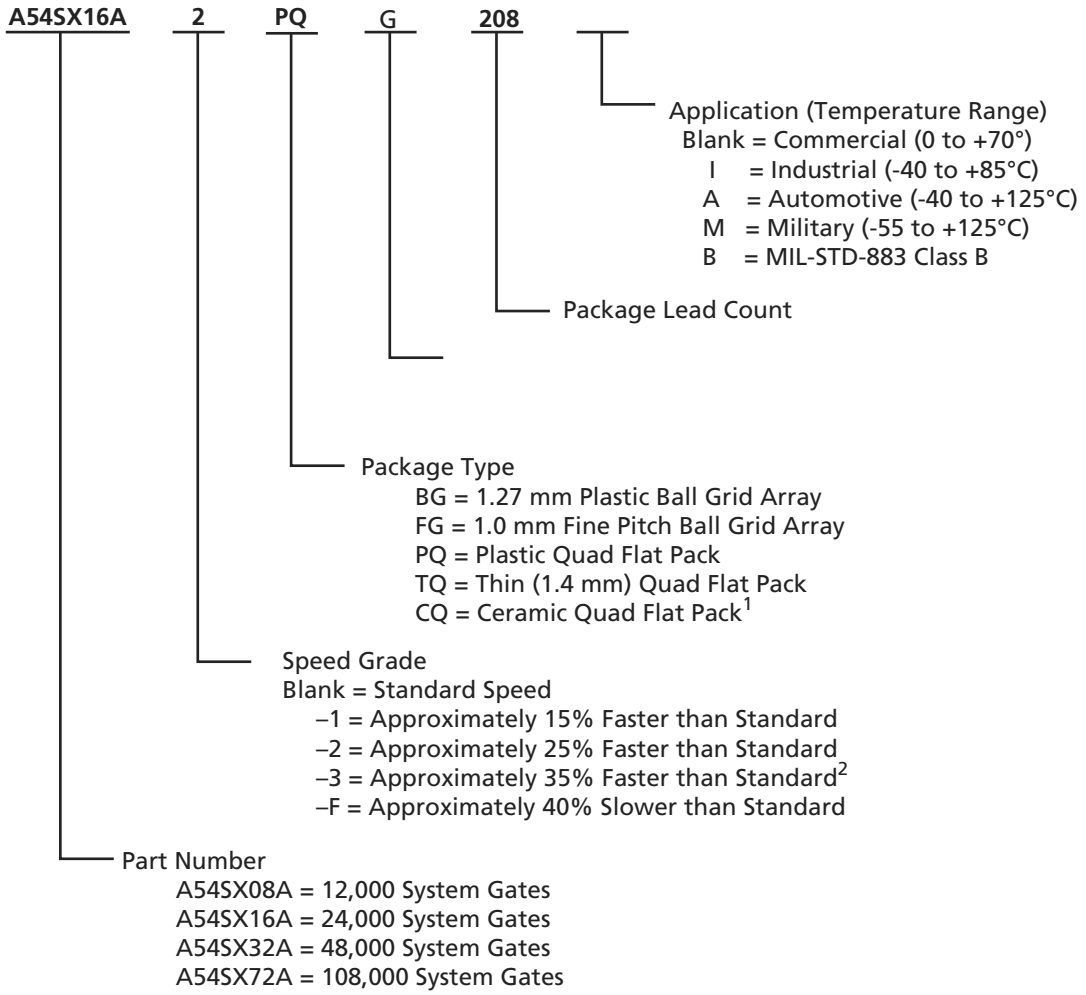
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	6036
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	171
Number of Gates	108000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx72a-1pqg208

Ordering Information



Notes:

1. *For more information about the CQFP package options, refer to the* HiRel SX-A datasheet.
2. *All –3 speed grades have been discontinued.*

Device Resources

	User I/Os (Including Clock Buffers)							
Device	**208-Pin PQFP**	**100-Pin TQFP**	**144-Pin TQFP**	**176-Pin TQFP**	**329-Pin PBGA**	**144-Pin FBGA**	**256-Pin FBGA**	**484-Pin FBGA**
A54SX08A	130	81	113	–	–	111	–	–
A54SX16A	175	81	113	–	–	111	180	–
A54SX32A	174	81	113	147	249	111	203	249
A54SX72A	171	–	–	–	–	–	203	360

Notes: *Package Definitions: PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array, FBGA = Fine Pitch Ball Grid Array*

Temperature Grade Offering

Package	A54SX08A	A54SX16A	A54SX32A	A54SX72A
PQ208	C,I,A,M	C,I,A,M	C,I,A,M	C,I,A,M
TQ100	C,I,A,M	C,I,A,M	C,I,A,M	
TQ144	C,I,A,M	C,I,A,M	C,I,A,M	
TQ176			C,I,M	
BG329			C,I,M	
FG144	C,I,A,M	C,I,A,M	C,I,A,M	
FG256		C,I,A,M	C,I,A,M	C,I,A,M
FG484			C,I,M	C,I,A,M
CQ208			C,M,B	C,M,B
CQ256			C,M,B	C,M,B

Notes:

1. *C = Commercial*
2. *I = Industrial*
3. *A = Automotive*
4. *M = Military*
5. *B = MIL-STD-883 Class B*
6. *For more information regarding automotive products, refer to the* SX-A Automotive Family FPGAs *datasheet.*
7. *For more information regarding Mil-Temp and ceramic packages, refer to the* HiRel SX-A Family FPGAs *datasheet.*

Speed Grade and Temperature Grade Matrix

	F	Std	–1	–2	–3
Commercial	✓	✓	✓	✓	Discontinued
Industrial		✓	✓	✓	Discontinued
Automotive		✓			
Military		✓	✓		
MIL-STD-883B		✓	✓		

Notes:

1. *For more information regarding automotive products, refer to the* SX-A Automotive Family FPGAs *datasheet.*
2. *For more information regarding Mil-Temp and ceramic packages, refer to the* HiRel SX-A Family FPGAs *datasheet.*

Contact your Actel Sales representative for more information on availability.

Probing Capabilities

SX-A devices also provide an internal probing capability that is accessed with the JTAG pins. The Silicon Explorer II diagnostic hardware is used to control the TDI, TCK, TMS, and TDO pins to select the desired nets for debugging. The user assigns the selected internal nets in Actel Silicon Explorer II software to the PRA/PRB output pins for observation. Silicon Explorer II automatically places the device into JTAG mode. However, probing functionality is only activated when the TRST pin is driven high or left floating, allowing the internal pull-up resistor to pull TRST High. If the TRST pin is held Low, the TAP controller remains in the Test-Logic-Reset state so no probing can be performed. However, the user must drive the TRST pin High or allow the internal pull-up resistor to pull TRST High.

When selecting the **Reserve Probe Pin** box as shown in Figure 1-12 on page 1-9, direct the layout tool to reserve the PRA and PRB pins as dedicated outputs for probing. This **Reserve** option is merely a guideline. If the designer assigns user I/Os to the PRA and PRB pins and selects the **Reserve Probe Pin** option, Designer Layout will override the **Reserve Probe Pin** option and place the user I/Os on those pins.

To allow probing capabilities, the security fuse must not be programmed. Programming the security fuse disables the JTAG and probe circuitry. Table 1-9 summarizes the possible device configurations for probing once the device leaves the Test-Logic-Reset JTAG state.

Table 1-9 • **Device Configuration Options for Probe Capability (TRST Pin Reserved)**

JTAG Mode	TRST[1]	Security Fuse Programmed	PRA, PRB[2]	TDI, TCK, TDO[2]
Dedicated	Low	No	User I/O[3]	JTAG Disabled
	High	No	Probe Circuit Outputs	JTAG I/O
Flexible	Low	No	User I/O[3]	User I/O[3]
	High	No	Probe Circuit Outputs	JTAG I/O
		Yes	Probe Circuit Secured	Probe Circuit Secured

Notes:

1. *If the TRST pin is not reserved, the device behaves according to TRST = High as described in the table.*
2. *Avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.*
3. *If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. Unused pins are automatically tristated by the Designer software.*

Design Environment

The SX-A family of FPGAs is fully supported by both Actel Libero® Integrated Design Environment (IDE) and Designer FPGA development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Additionally, Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw® for Actel from Mentor Graphics®, Model*Sim*® HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the *Libero IDE flow* diagram for more information (located on the Actel website).

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators and the simulation results can be cross-probed with Silicon Explorer II, Actel's integrated verification and logic analysis tool. Another tool included in the Designer software is the SmarGen core generator, which easily creates popular and commonly used logic functions for implementation in your schematic or HDL design. Actel's Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys, and Cadence Design Systems. The Designer software is available for both the Windows and UNIX operating systems.

Programming

Device programming is supported through Silicon Sculptor series of programmers. In particular, Silicon Sculptor is compact, robust, single-site and multi-site device programmer for the PC.

With standalone software, Silicon Sculptor allows concurrent programming of multiple units from the same PC, ensuring the fastest programming times possible. Each fuse is subsequently verified by Silicon Sculptor II to insure correct programming. In addition, integrity tests ensure that no extra fuses are programmed. Silicon Sculptor also provides extensive hardware self-testing capability.

The procedure for programming an SX-A device using Silicon Sculptor is as follows:

1. Load the .AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Actel offers device volume-programming services either through distribution partners or via in-house programming from the factory.

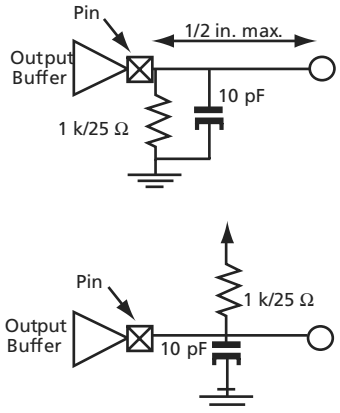
For detailed information on programming, read the following documents *Programming Antifuse Devices* and *Silicon Sculptor User's Guide*.

Table 2-10 • **AC Specifications (3.3 V PCI Operation)**

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \le 0.3V_{CCI}$ [1]	$-12V_{CCI}$	–	mA
		$0.3V_{CCI} \le V_{OUT} < 0.9V_{CCI}$ [1]	$(-17.1(V_{CCI} - V_{OUT}))$	–	mA
		$0.7V_{CCI} < V_{OUT} < V_{CCI}$ [1, 2]	–	EQ 2-3 on page 2-7	–
	(Test Point)	$V_{OUT} = 0.7V_{CC}$ [2]	–	$-32V_{CCI}$	mA
$I_{OL(AC)}$	Switching Current Low	$V_{CCI} > V_{OUT} \ge 0.6V_{CCI}$ [1]	$16V_{CCI}$	–	mA
		$0.6V_{CCI} > V_{OUT} > 0.1V_{CCI}$ [1]	$(26.7V_{OUT})$	–	mA
		$0.18V_{CCI} > V_{OUT} > 0$ [1, 2]	–	EQ 2-4 on page 2-7	–
	(Test Point)	$V_{OUT} = 0.18V_{CC}$ [2]	–	$38V_{CCI}$	mA
I_{CL}	Low Clamp Current	$-3 < V_{IN} \le -1$	$-25 + (V_{IN} + 1)/0.015$	–	mA
I_{CH}	High Clamp Current	$V_{CCI} + 4 > V_{IN} \ge V_{CCI} + 1$	$25 + (V_{IN} - V_{CCI} - 1)/0.015$	–	mA
$slew_R$	Output Rise Slew Rate	$0.2V_{CCI}$ - $0.6V_{CCI}$ load [3]	1	4	V/ns
$slew_F$	Output Fall Slew Rate	$0.6V_{CCI}$ - $0.2V_{CCI}$ load [3]	1	4	V/ns

Notes:

1. *Refer to the V/I curves in Figure 2-2 on page 2-7. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.*
2. *Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (C and D) are provided with the respective diagrams in Figure 2-2 on page 2-7. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.*
3. *This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per the latest revision of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is required (the maximum is no longer simply a guideline). Rise slew rate does not apply to open drain outputs.*



Power Dissipation

A critical element of system reliability is the ability of electronic devices to safely dissipate the heat generated during operation. The thermal characteristics of a circuit depend on the device and package used, the operating temperature, the operating current, and the system's ability to dissipate heat.

A complete power evaluation should be performed early in the design process to help identify potential heat-related problems in the system and to prevent the system from exceeding the device's maximum allowed junction temperature.

The actual power dissipated by most applications is significantly lower than the power the package can dissipate. However, a thermal analysis should be performed for all projects. To perform a power evaluation, follow these steps:

1. Estimate the power consumption of the application.
2. Calculate the maximum power allowed for the device and package.
3. Compare the estimated power and maximum power values.

Estimating Power Dissipation

The total power dissipation for the SX-A family is the sum of the DC power dissipation and the AC power dissipation:

$$P_{Total} = P_{DC} + P_{AC}$$

EQ 2-5

DC Power Dissipation

The power due to standby current is typically a small component of the overall power. An estimation of DC power dissipation under typical conditions is given by:

$$P_{DC} = I_{Standby} * V_{CCA}$$

EQ 2-6

Note: For other combinations of temperature and voltage settings, refer to the *eX, SX-A and RT54SX-S Power Calculator*.

AC Power Dissipation

The power dissipation of the SX-A family is usually dominated by the dynamic power dissipation. Dynamic power dissipation is a function of frequency, equivalent capacitance, and power supply voltage. The AC power dissipation is defined as follows:

$$P_{AC} = P_{C\text{-cells}} + P_{R\text{-cells}} + P_{CLKA} + P_{CLKB} + P_{HCLK} + P_{Output\ Buffer} + P_{Input\ Buffer}$$

EQ 2-7

or:

$$P_{AC} = V_{CCA}^2 * [(m * C_{EQCM} * fm)_{C\text{-cells}} + (m * C_{EQSM} * fm)_{R\text{-cells}} + (n * C_{EQI} * f_n)_{Input\ Buffer} + (p * (C_{EQO} + C_L) * f_p)_{Output\ Buffer} + (0.5 * (q_1 * C_{EQCR} * f_{q1}) + (r_1 * f_{q1}))_{CLKA} + (0.5 * (q_2 * C_{EQCR} * f_{q2}) + (r_2 * f_{q2}))_{CLKB} + (0.5 * (s_1 * C_{EQHV} * f_{s1}) + (C_{EQHF} * f_{s1}))_{HCLK}]$$

EQ 2-8

Where:

C_{EQCM} = Equivalent capacitance of combinatorial modules (C-cells) in pF

C_{EQSM} = Equivalent capacitance of sequential modules (R-Cells) in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of CLKA/B in pF

C_{EQHV} = Variable capacitance of HCLK in pF

C_{EQHF} = Fixed capacitance of HCLK in pF

C_{L} = Output lead capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average CLKA rate in MHz

f_{q2} = Average CLKB rate in MHz

f_{s1} = Average HCLK rate in MHz

m = Number of logic modules switching at fm

n = Number of input buffers switching at fn

p = Number of output buffers switching at fp

q_1 = Number of clock loads on CLKA

q_2 = Number of clock loads on CLKB

r_1 = Fixed capacitance due to CLKA

r_2 = Fixed capacitance due to CLKB

s_1 = Number of clock loads on HCLK

x = Number of I/Os at logic low

y = Number of I/Os at logic high

Table 2-11 • **CEQ Values for SX-A Devices**

	A54SX08A	**A54SX16A**	**A54SX32A**	**A54SX72A**
Combinatorial modules (C_{EQCM})	1.70 pF	2.00 pF	2.00 pF	1.80 pF
Sequential modules (C_{EQCM})	1.50 pF	1.50 pF	1.30 pF	1.50 pF
Input buffers (C_{EQI})	1.30 pF	1.30 pF	1.30 pF	1.30 pF
Output buffers (C_{EQO})	7.40 pF	7.40 pF	7.40 pF	7.40 pF
Routed array clocks (C_{EQCR})	1.05 pF	1.05 pF	1.05 pF	1.05 pF
Dedicated array clocks – variable (C_{EQHV})	0.85 pF	0.85 pF	0.85 pF	0.85 pF
Dedicated array clocks – fixed (C_{EQHF})	30.00 pF	55.00 pF	110.00 pF	240.00 pF
Routed array clock A (r_1)	35.00 pF	50.00 pF	90.00 pF	310.00 pF

Table 2-21 • **A54SX16A Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.7		0.8		0.9		1.1		1.5	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.5		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		0.7		0.8		0.9		1.1		1.5	ns
Input Module Predicted Routing Delays[2]												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		0.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2.0		2.2		2.6		3.6	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-25 • **A54SX16A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 2.25 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing [2, 3]												
t_{DLH}	Data-to-Pad Low to High		3.4		3.9		4.5		5.2		7.3	ns
t_{DHL}	Data-to-Pad High to Low		2.6		3.0		3.3		3.9		5.5	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		11.6		13.4		15.2		17.9		25.0	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.4		2.8		3.2		3.7		5.2	ns
t_{ENZLS}	Data-to-Pad, Z to L—low slew		11.8		13.7		15.5		18.2		25.5	ns
t_{ENZH}	Enable-to-Pad, Z to H		3.4		3.9		4.5		5.2		7.3	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.1		2.5		2.8		3.3		4.7	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.6		3.0		3.3		3.9		5.5	ns
d_{TLH}[4]	Delta Low to High		0.031		0.037		0.043		0.051		0.071	ns/pF
d_{THL}[4]	Delta High to Low		0.017		0.017		0.023		0.023		0.037	ns/pF
d_{THLS}[4]	Delta High to Low—low slew		0.057		0.06		0.071		0.086		0.117	ns/pF

Note:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 35 pF loading.*
3. *The equivalent IO Attribute settings for 2.5 V LVCMOS is 2.5 V LVTTL in the software.*
4. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-26 • **A54SX16A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
3.3 V PCI Output Module Timing[2]												
t_{DLH}	Data-to-Pad Low to High		2.0		2.3		2.6		3.1		4.3	ns
t_{DHL}	Data-to-Pad High to Low		2.2		2.5		2.8		3.3		4.6	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.4		1.7		1.9		2.2		3.1	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.0		2.3		2.6		3.1		4.3	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.5		2.8		3.2		3.8		5.3	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.2		2.5		2.8		3.3		4.6	ns
d_{TLH}[3]	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d_{THL}[3]	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
3.3 V LVTTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad Low to High		2.8		3.2		3.6		4.3		6.0	ns
t_{DHL}	Data-to-Pad High to Low		2.7		3.1		3.5		4.1		5.7	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		9.5		10.9		12.4		14.6		20.4	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.2		2.6		2.9		3.4		4.8	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		15.8		18.9		21.3		25.4		34.9	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.8		3.2		3.6		4.3		6.0	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.9		3.3		3.7		4.4		6.2	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.7		3.1		3.5		4.1		5.7	ns
d_{TLH}[3]	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d_{THL}[3]	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
d_{THLS}[3]	Delta High to Low—low slew		0.053		0.053		0.067		0.073		0.107	ns/pF

Notes:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 10 pF loading and 25 Ω resistance.*
3. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. *Delays based on 35 pF loading.*

Table 2-28 • **A54SX32A Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.9		1.1		1.2		1.4		1.9	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.9		1.1		1.2		1.4		1.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		1.4		1.6		1.8		2.1		2.9	ns
Input Module Predicted Routing Delays[3]												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2		2.2		2.6		3.6	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-31 • **A54SX32A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)**

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t_{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		1.9		2.2		2.6		4.0	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t_{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t_{HPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t_{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns
t_{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns
f_{HMAX}	Maximum Frequency		357		313		278		238		172	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.7	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.5		2.8		3.3		4.5	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.4		2.7		3.1		3.6		5.1	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.6		2.9		3.4		4.7	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.5		2.8		3.2		3.8		5.3	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.8		3.1		3.7		5.2	ns
t_{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t_{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t_{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns
t_{RCKSW}	Maximum Skew (50% Load)		1.0		1.1		1.3		1.5		2.1	ns
t_{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: **All –3 speed grades have been discontinued.*

Table 2-38 • **A54SX72A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)**

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t_{HCKH}	Input Low to High (Pad to R-cell Input)		1.6		1.8		2.1		2.4		3.8	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.8	ns
t_{HPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{HPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{HCKSW}	Maximum Skew		1.4		1.6		1.8		2.1		3.3	ns
t_{HP}	Minimum Period	3.0		3.4		4.0		4.6		6.4		ns
f_{HMAX}	Maximum Frequency		333		294		250		217		156	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.3		2.6		3.0		3.5		4.9	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.8		3.2		3.6		4.3		6.0	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.5		2.9		3.2		3.8		5.3	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.6		3.0		3.4		3.9		5.5	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		3.2		3.6		4.1		4.8		6.8	ns
t_{RPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{RPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{RCKSW}	Maximum Skew (Light Load)		1.9		2.2		2.5		3.0		4.1	ns
t_{RCKSW}	Maximum Skew (50% Load)		1.9		2.2		2.5		3.0		4.1	ns
t_{RCKSW}	Maximum Skew (100% Load)		1.9		2.2		2.5		3.0		4.1	ns
Quadrant Array Clock Networks												
t_{QCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.6	ns
t_{QCHKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.3		1.4		1.6		1.9		2.7	ns
t_{QCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.4		1.6		1.8		2.1		3.0	ns
t_{QCHKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.4		1.7		1.9		2.2		3.1	ns

Note: **All –3 speed grades have been discontinued.*

Table 2-39 • **A54SX72A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 2.3 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing[2, 3]												
t_{DLH}	Data-to-Pad Low to High		3.9		4.5		5.1		6.0		8.4	ns
t_{DHL}	Data-to-Pad High to Low		3.1		3.6		4.1		4.8		6.7	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		12.7		14.6		16.5		19.4		27.2	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.4		2.8		3.2		3.7		5.2	ns
t_{ENZLS}	Data-to-Pad, Z to L—low slew		11.8		13.7		15.5		18.2		25.5	ns
t_{ENZH}	Enable-to-Pad, Z to H		3.9		4.5		5.1		6.0		8.4	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.1		2.5		2.8		3.3		4.7	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.1		3.6		4.1		4.8		6.7	ns
d_{TLH}[4]	Delta Low to High		0.031		0.037		0.043		0.051		0.071	ns/pF
d_{THL}[4]	Delta High to Low		0.017		0.017		0.023		0.023		0.037	ns/pF
d_{THLS}[4]	Delta High to Low—low slew		0.057		0.06		0.071		0.086		0.117	ns/pF

Note:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 35 pF loading.*
3. *The equivalent IO Attribute settings for 2.5 V LVCMOS is 2.5 V LVTTL in the software.*
4. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-41 • **A54SX72A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing[2]												
t_{DLH}	Data-to-Pad Low to High		2.7		3.1		3.5		4.1		5.7	ns
t_{DHL}	Data-to-Pad High to Low		3.4		3.9		4.4		5.1		7.2	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0		2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.7		3.1		3.5		4.1		5.7	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.4		3.9		4.4		5.1		7.2	ns
d_{TLH}[3]	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF
d_{THL}[3]	Delta High to Low		0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad Low to High		2.4		2.8		3.1		3.7		5.1	ns
t_{DHL}	Data-to-Pad High to Low		3.1		3.5		4.0		4.7		6.6	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		7.4		8.5		9.7		11.4		15.9	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.1		3.7		5.1	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.1		3.5		4.0		4.7		6.6	ns
d_{TLH}[3]	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF
d_{THL}[3]	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF
d_{THLS}[3]	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 50 pF loading.*
3. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. *Delays based on 35 pF loading.*

Package Pin Assignments

208-Pin PQFP

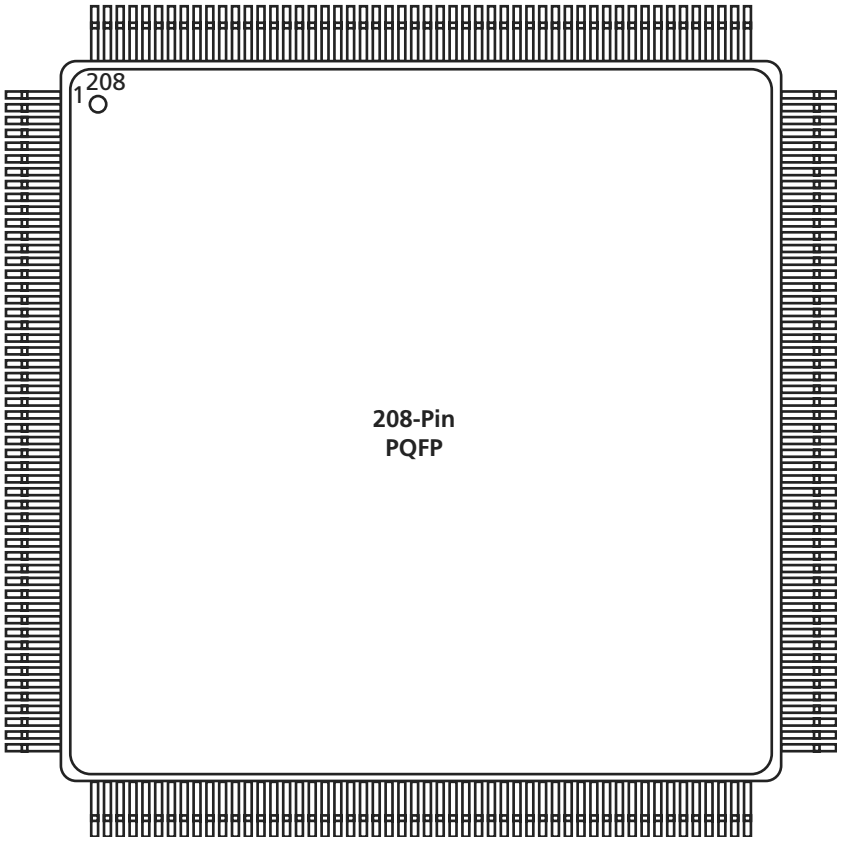


Figure 3-1 • **208-Pin PQFP (Top View)**

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.

144-Pin TQFP

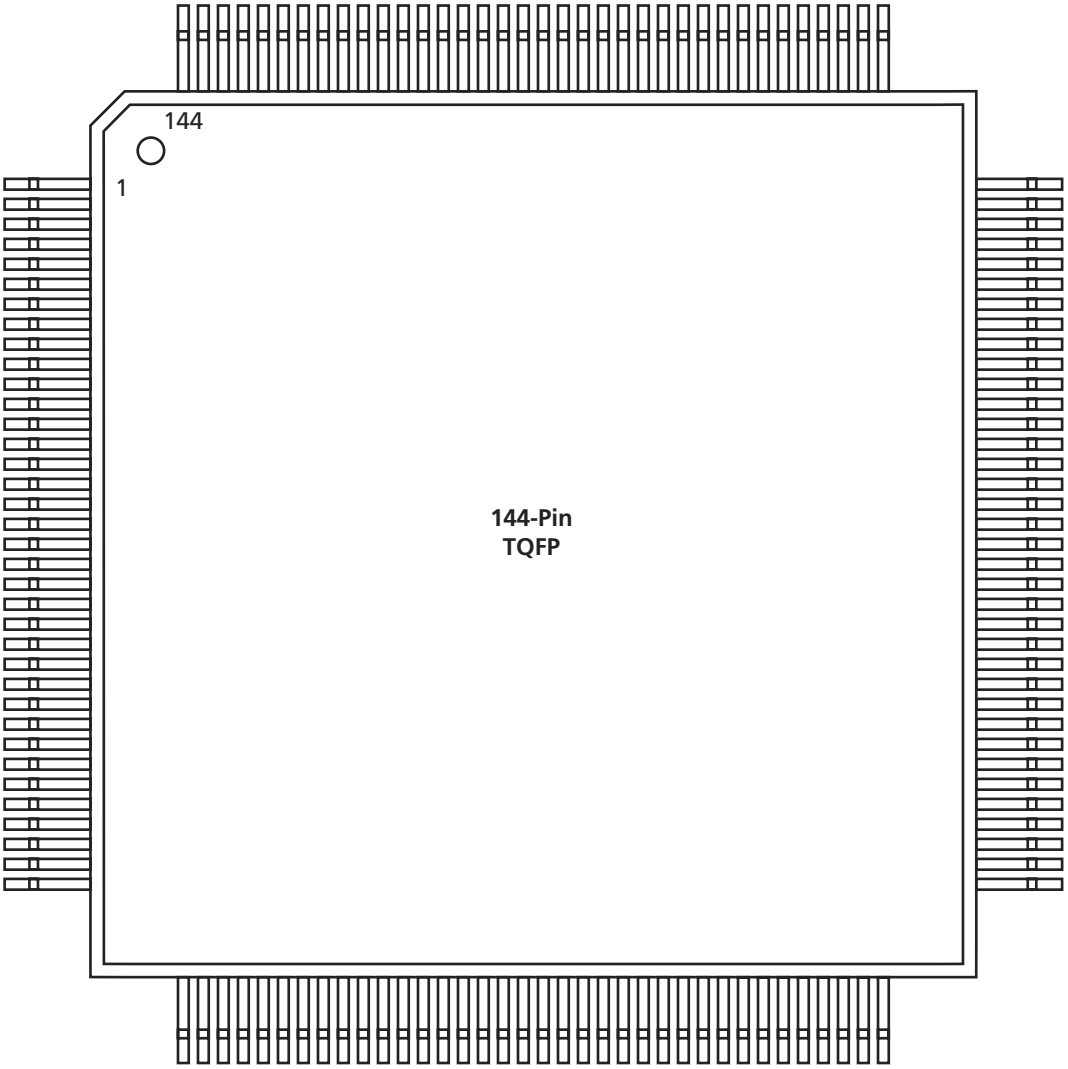


Figure 3-3 • **144-Pin TQFP (Top View)**

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.

176-Pin TQFP	
Pin Number	**A54SX32A Function**
1	GND
2	TDI, I/O
3	I/O
4	I/O
5	I/O
6	I/O
7	I/O
8	I/O
9	I/O
10	TMS
11	V_{CCI}
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	I/O
18	I/O
19	I/O
20	I/O
21	GND
22	V_{CCA}
23	GND
24	I/O
25	TRST, I/O
26	I/O
27	I/O
28	I/O
29	I/O
30	I/O
31	I/O
32	V_{CCI}
33	V_{CCA}
34	I/O
35	I/O
36	I/O

176-Pin TQFP	
Pin Number	**A54SX32A Function**
37	I/O
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	GND
45	I/O
46	I/O
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	V_{CCI}
53	I/O
54	I/O
55	I/O
56	I/O
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	PRB, I/O
65	GND
66	V_{CCA}
67	NC
68	I/O
69	HCLK
70	I/O
71	I/O
72	I/O

176-Pin TQFP	
Pin Number	**A54SX32A Function**
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	V_{CCI}
83	I/O
84	I/O
85	I/O
86	I/O
87	TDO, I/O
88	I/O
89	GND
90	I/O
91	I/O
92	I/O
93	I/O
94	I/O
95	I/O
96	I/O
97	I/O
98	V_{CCA}
99	V_{CCI}
100	I/O
101	I/O
102	I/O
103	I/O
104	I/O
105	I/O
106	I/O
107	I/O
108	GND

176-Pin TQFP	
Pin Number	**A54SX32A Function**
109	V_{CCA}
110	GND
111	I/O
112	I/O
113	I/O
114	I/O
115	I/O
116	I/O
117	I/O
118	I/O
119	I/O
120	I/O
121	I/O
122	V_{CCA}
123	GND
124	V_{CCI}
125	I/O
126	I/O
127	I/O
128	I/O
129	I/O
130	I/O
131	I/O
132	I/O
133	GND
134	I/O
135	I/O
136	I/O
137	I/O
138	I/O
139	I/O
140	V_{CCI}
141	I/O
142	I/O
143	I/O
144	I/O

256-Pin FBGA

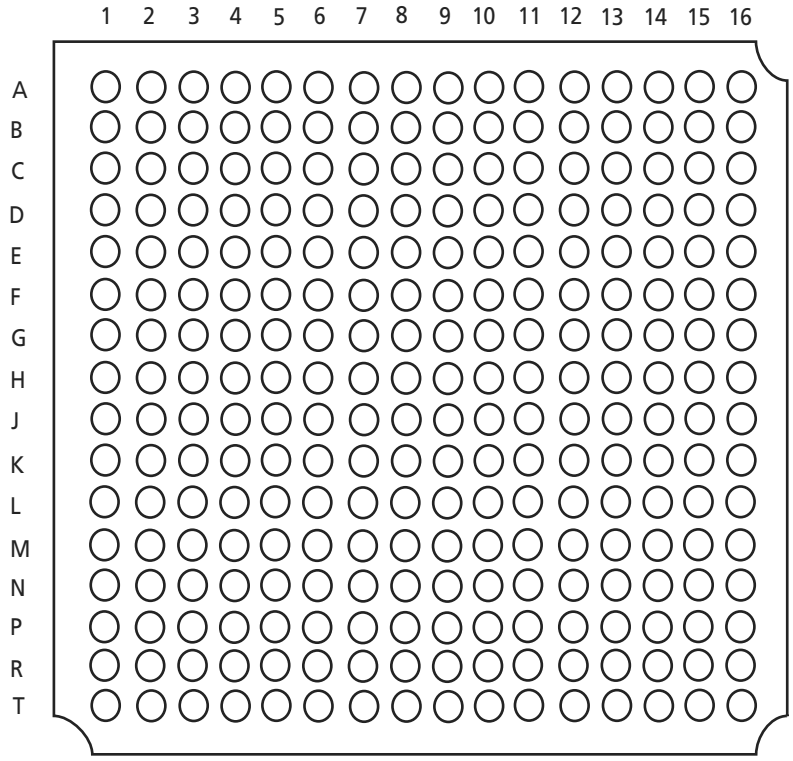


Figure 3-7 • **256-Pin FBGA (Top View)**

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.

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